



User-in-the-Loop View Sampling with Error Peaking Visualization

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Introduction







Focus peaking



Conventional AR visualizations [Mildenhall et al., 2019]

Background

- Goal: Explore view sampling strategy for novel view synthesis with fewer multi-view images
- Key idea: Augmented reality (AR) can provide ways to visualize missing view samples.
- Existing work: Determine view intervals according to the plenoptic sampling theory → Requiring uniform view sampling, thereby ignoring the structure of the target scene

Remaining challenges in AR visual guidance

- 1. Hide the subject to be photographed and hinder the entertaining nature of photography
- 2. The alignment task known to be mentally demanding.
- 3. The globally applied minimum view intervals that may not make sense at the moment.
- Fixed visualization limiting users' ability to explore beyond predetermined areas

Contribution

AR-based error-peaking visualization of the area of imperfect local light field reconstruction inspired by the focus peaking visualization for tuning the in-focus of camera lens

Proposed Method

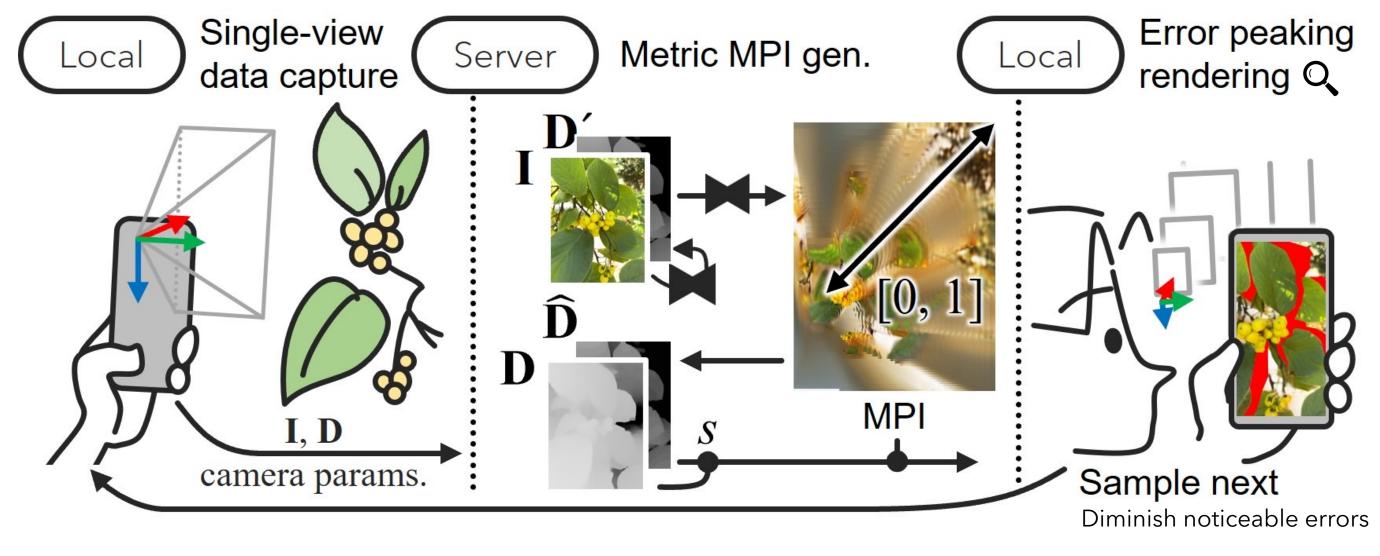


Fig. User-in-the-loop view sampling system overview

Metric MPI Generation

Single-view data

Our system allows users to capture single-view data (RGB image I, and metric depth map D) on AR-supported mobile phone.

Multi-Plane Images (MPI) from single-view data

Given I and \mathbf{D} , we generate an MPI using AdaMPI [Han et al., 2022].

Blending multiple MPI

To avoid frequent switching artifacts between the nearest MPI to another, \rightarrow Blending k nearest MPI volumes (k = 3 by default).

Error Peaking Visualization for Next View Samples Q

- 1. Calculate the difference between the video frame and MPI rendering
- 2. Highlight pixels with significant errors in red
- 3. Diminish these errors by inserting more view samples.

View synthesis quality

Dataset:

We recorded a real image dataset with varying depths and camera motions. We evaluated the rendering quality of MPI and 3D Gaussian splatting (3DGS).

Result:

Our approach produces fewer artifacts than Uniform (corresponds to LLFF) and Random.

Table. View synthesis quality of different view sampling strategies

Method (MPI)	PSNR (†)	SSIM (†)	LPIPS (↓)
Random	0.89 (0.73)	0.92 (0.56)	1.09 (0.67)
Uniform	0.97(0.87)	0.96 (0.78)	1.03 (0.86)
Ours	1.00 (1.00)	1.00 (1.00)	1.00 (1.00)
Method (3DGS)	PSNR (†)	SSIM (†)	LPIPS (↓)
Random	0.92 (1.74)	0.986 (1.98)	1.30 (1.96)
Uniform	0.96 (1.27)	0.997 (1.12)	1.09 (1.28)
Ours	1.00 (1.00)	1.00 (1.00)	1.00 (1.00)

Desk (Eval: 30)

Fig. 3DGS rendering results

User Study

Goal: We validate the capability of users to spontaneously sample views under our error-peaking visualization in a user study.

Baseline implementation: The LLFF visual guidance based on plenoptic sampling theory

Metrics

- Usability: SUS, NASA-TLX Completion time: TCT, NCT
- Self-Confidence: "Q. The captured results will meet my expectations."
- "Q. The captured results met my expectations." Satisfaction:
- "Q. I focused on the scene of interest while capturing. ." Scene Focus:

Participants:

We collected 20 participants (five female and 15 male, $\bar{X} = 22.4$ (SD=1.4) years old, all right-handed and corrected vision).

Scene: Designed an office scene with varying depths during the scene capture.

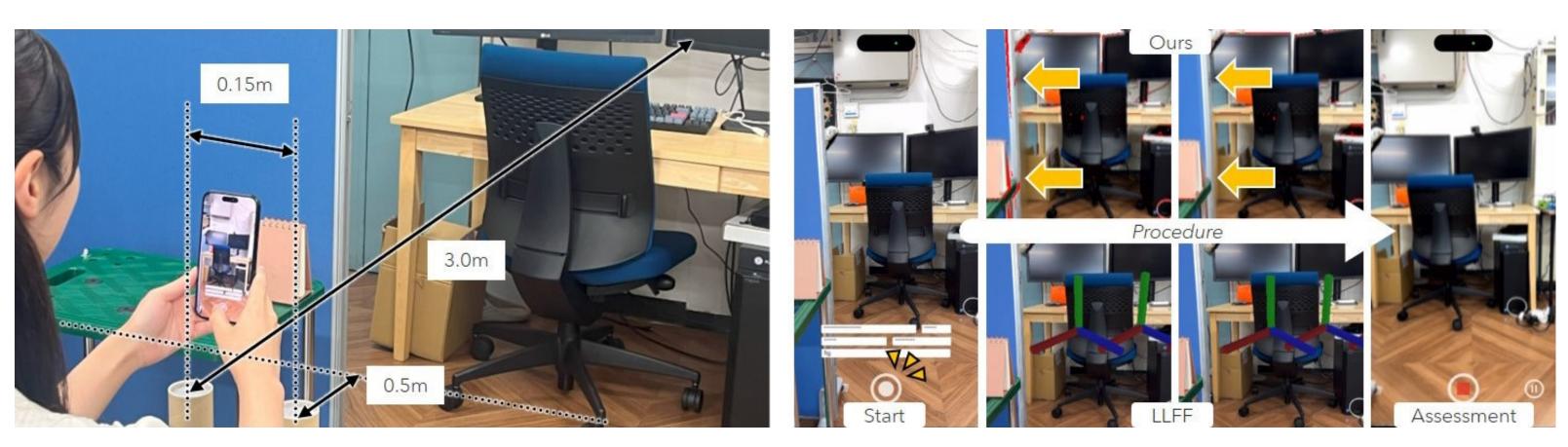


Fig. Experimental setup and procedure

Result:

Ours gives higher self-confidence during view sampling with better scene focus and lower disappointment in the final rendering quality with fewer views.

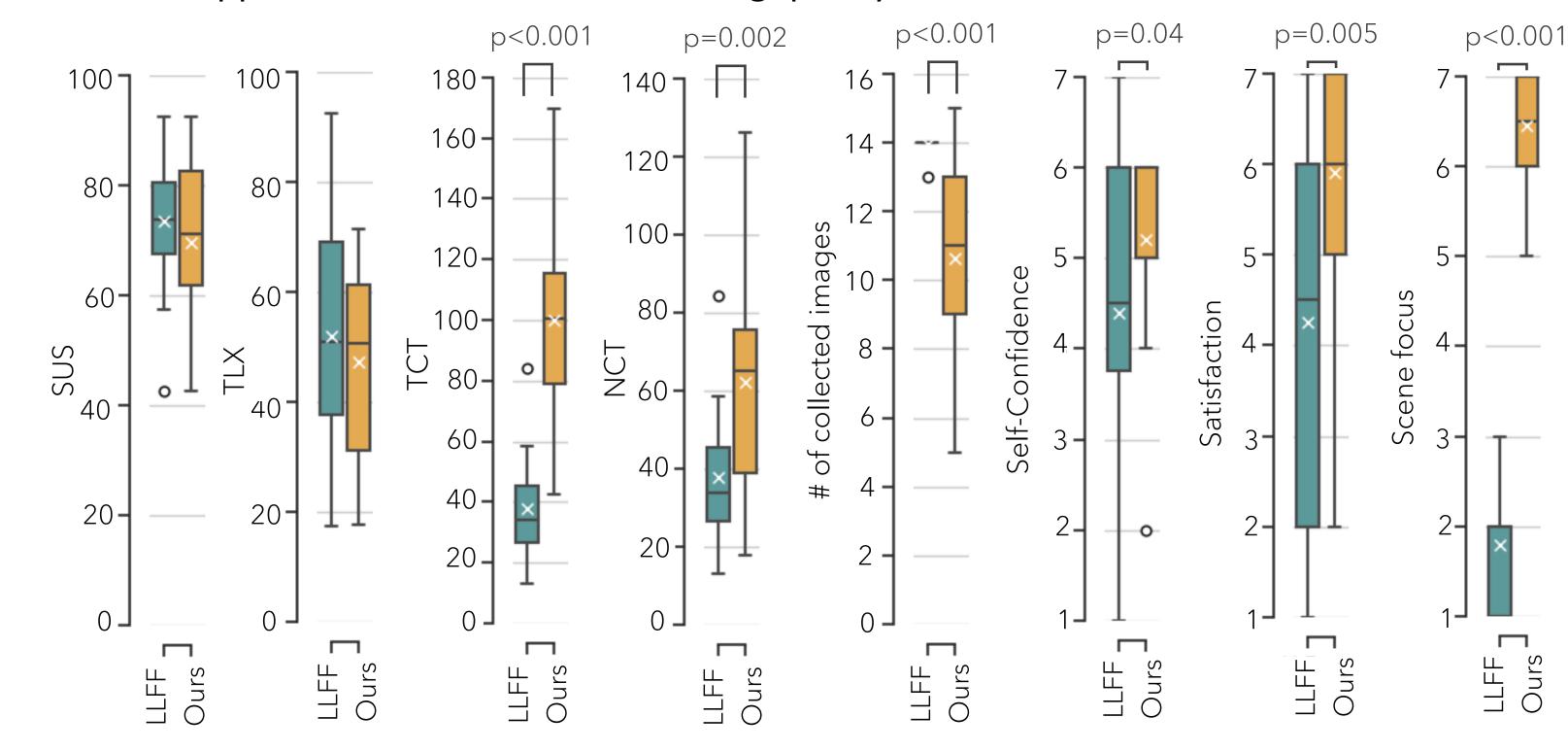


Fig. User study results

Limitations

Latency in communication and network inference

- Our system still experiences delays
 - Due to **network inference** and **communication time** between the server and the client.

Further user analysis

Missing factors: the screen resolution, the distance from the AR display to the users' eyes, and the users' motion while observing the results

Contact

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